Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
	SHEN, CHE-KUN JAMES	S
Examiner ·	Art Unit	
Sumesh Kaushal Ph D	1633	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
STN:- MEDLINE, CAPLUS, SCISEARCH, CAPLUS, BIOSIS. EAST:- USPAT, PGPUB, EPO, JPO, DERWENT. STIC Sequence search report. Inventor name search. see attachment.	12/1/2006	sĸ
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